

29.11.2016

# CT X-Ray Spectrum Reconstruction with High Frequency Components

Carsten Leinweber, Joscha Maier,  
and Marc Kachelrieß

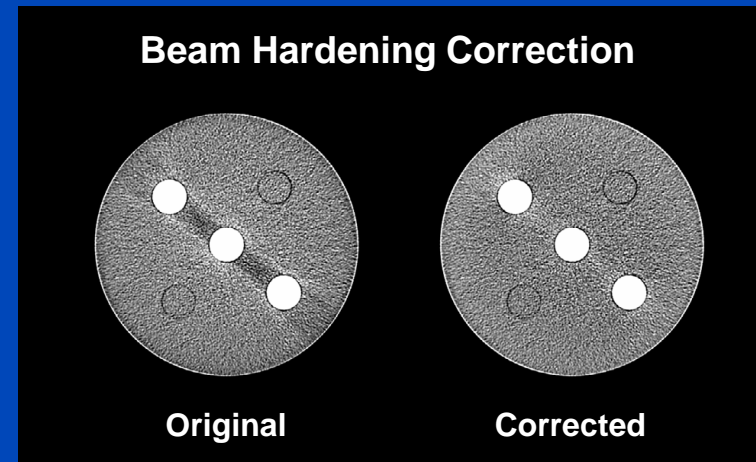
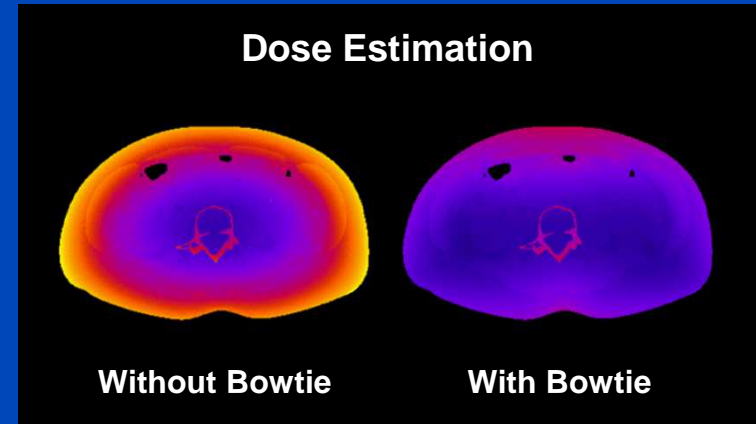
German Cancer Research Center (DKFZ), Heidelberg, Germany



DEUTSCHES  
KREBSFORSCHUNGSZENTRUM  
IN DER HELMHOLTZ-GEMEINSCHAFT

# Introduction

- CT applications that require accurate knowledge of the emitted or detected spectrum:
  - Organ dose estimation
  - Beam hardening correction
  - Dual energy decomposition
  - K-edge imaging
  - Quantitative perfusion measurements
  - ...
- Existing methods:
  - Semi-analytic models
  - Monte-Carlo simulation
  - Spectroscopy
  - Compton scattering
  - **Transmission measurements (direct, simple, no extra hardware)**
  - ...



# Spectrum Reconstruction from Transmission Measurements

- Lambert-Beer law:

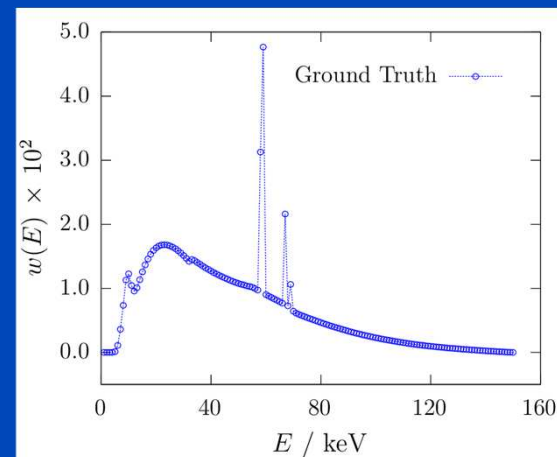
$$\tau_m = \frac{N_m}{N_0} = \sum_{b=1}^B e^{-\mu_{mb} d_m} w_b$$

- Problem:

“Given  $\tau$  for different (known) combinations of  $\mu(E)$  and  $d$ , reconstruct  $w(E)$ .”

- Methods:

- Few parameter modelling
- Neural networks
- Expectation maximization (EM)
- Truncated singular value decomposition (TSVD)
- New: PTSVD



# Truncated Singular Value Decomposition (TSVD)

- Discretized Lambert-Beer law in matrix notation:

$$\tau_m = \sum_{b=1}^B a_{mb} w_b \longrightarrow \tau = A \cdot w$$

- Minimize the least square difference

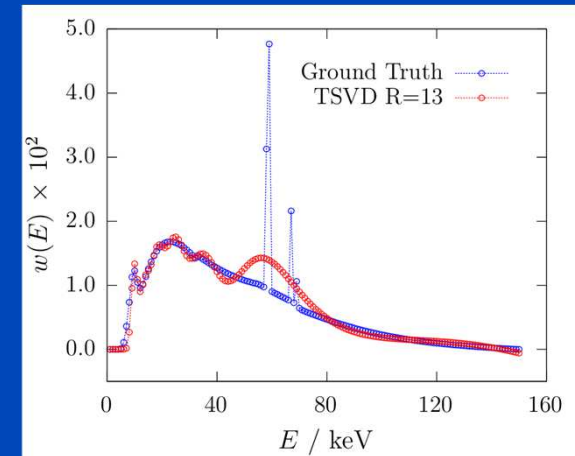
$$w = \arg \min_w \|A \cdot w - \tau\|_2^2 \longrightarrow w = A^+ \cdot \tau$$

- Calculation of the pseudo-inverse  $A^+$ 
  - Decompose  $A$  into orthonormal basis with help of SVD:

$$A = \sum_{b=1}^B u_b \cdot s_b v_b^T$$

- Truncate  $A^+$  to the highest  $R$  singular values:

$$w = \sum_{b=1}^R \left( v_b \cdot \frac{u_b^T}{s_b} \right) \cdot \tau \quad R \leq B$$



# Prior Truncated Singular Value Decomposition (PTSVD)

- Minimize the weighted least square difference with help of TSVD to obtain the low frequent solution from range:

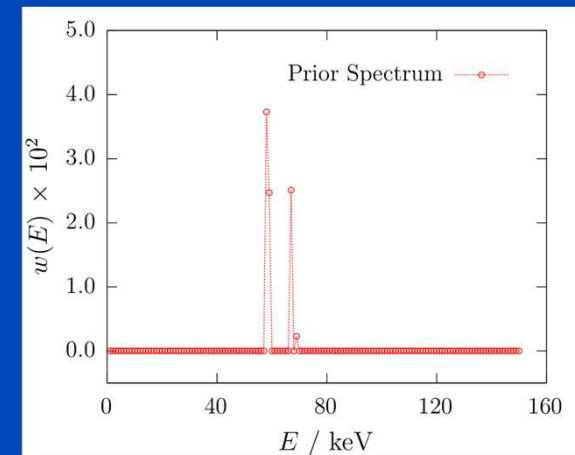
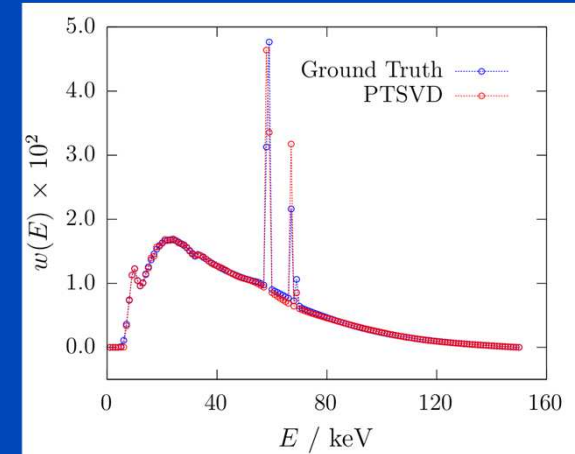
$$w_R = \arg \min_w \|A \cdot w - \tau\|_W^2 \quad \text{with} \quad W = \text{Cov}(\tau, \tau)^{-1}$$

- Calculate a solution from null space that represents the high frequency components (here: characteristic peaks):

$$w_N = \sum_{b=R+1}^B (v_b^T \cdot w_H) v_b$$

- Add the solution from null space to the solution from range:

$$w = w_R + w_N$$



## Materials and Methods

# Prior Truncated Singular Value Decomposition (PTSVD)

- We model the prior spectrum:

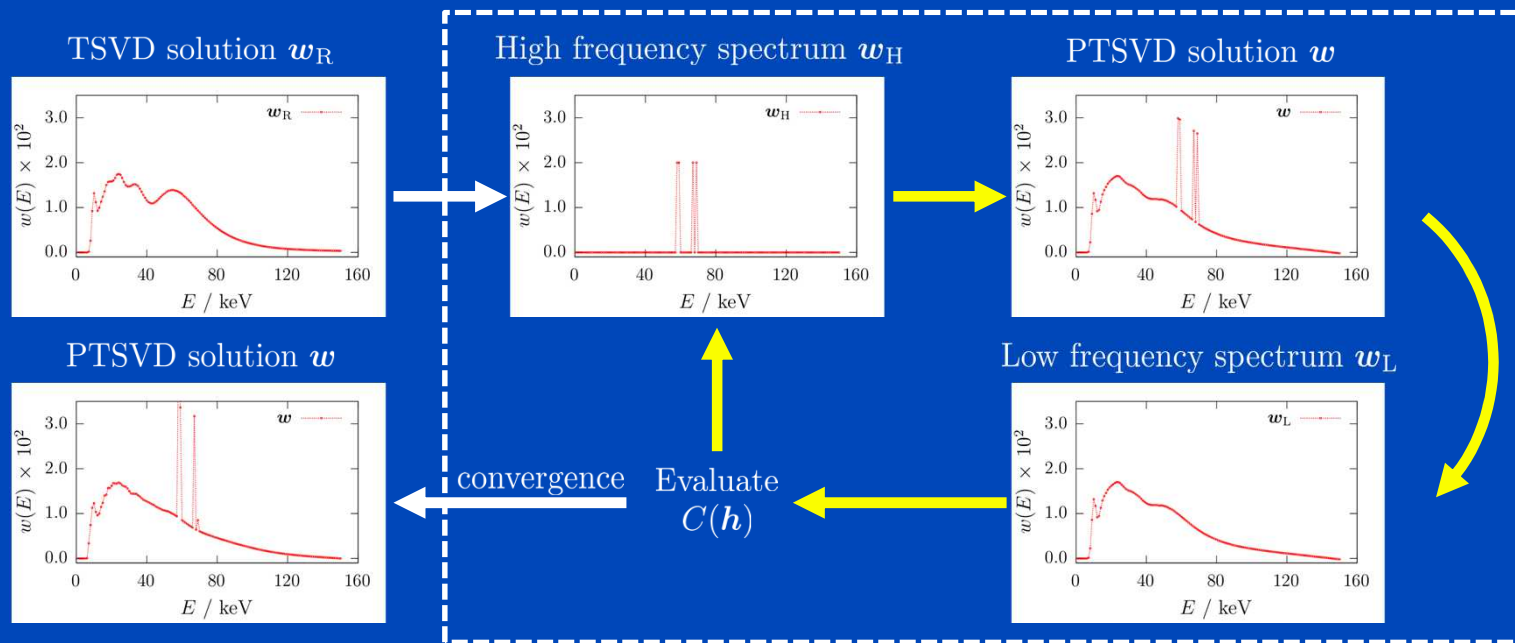
$$\mathbf{w}_H(\mathbf{h}) = \sum_{p=1}^P h_p \mathbf{e}_p$$

- Cost function

$$C(\mathbf{h}) = \underbrace{\|\mathbf{w}_L(\mathbf{h}) \wedge \mathbf{0}\|_2^2}_{\text{Non-negativity}} + \lambda \underbrace{\|\nabla \cdot \mathbf{w}_L(\mathbf{h})\|_2^2}_{\text{Smoothness}}$$

$$\mathbf{w}_L(\mathbf{h}) = \mathbf{w}(\mathbf{h}) - \mathbf{w}_H(\mathbf{h})$$

- Iteration schema:



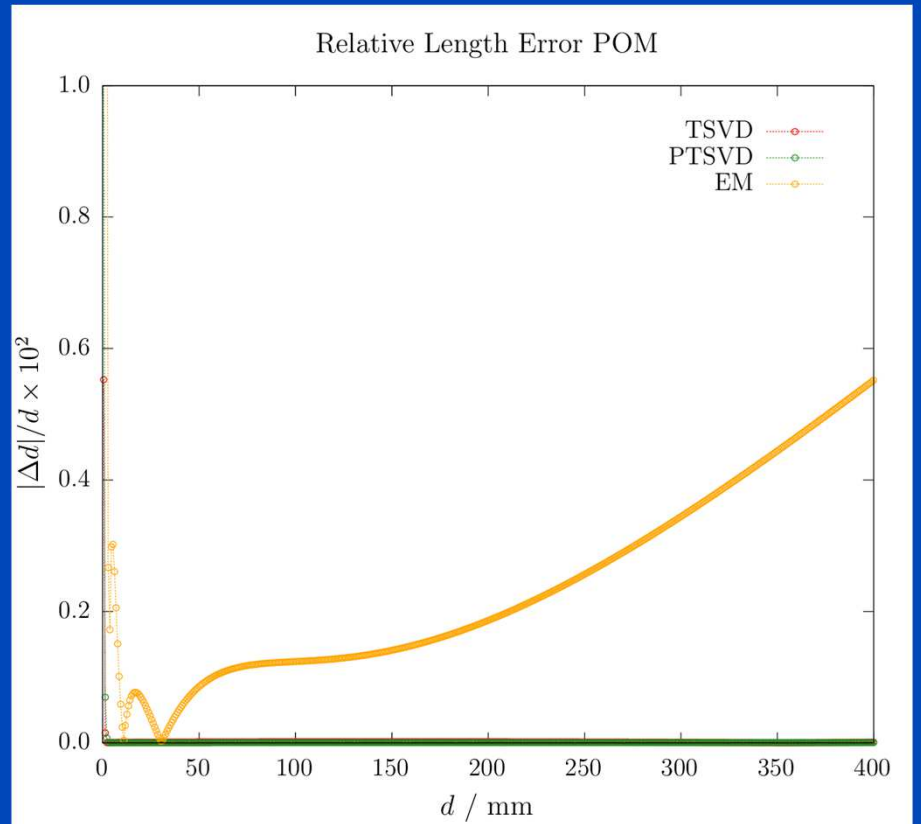
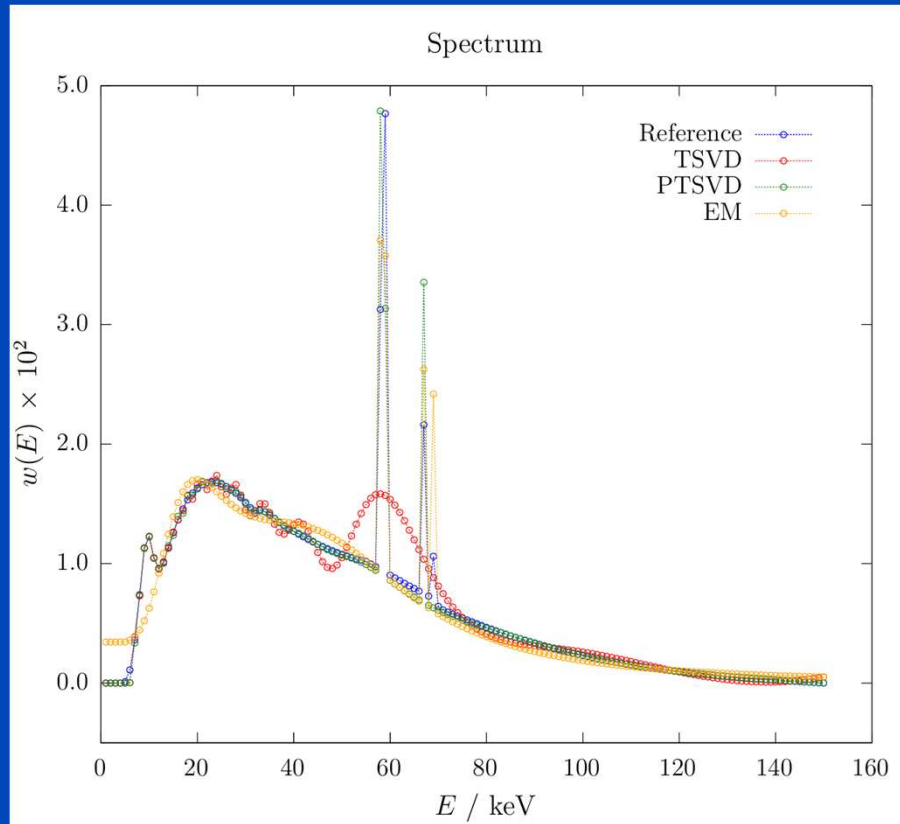
## Materials and Methods

# Simulation / Measurement Study

- **Simulation conditions:**
  - 150 kV tungsten target spectrum simulated according to Tucker et al.
  - Spectrum estimation from 28 aluminum (Al) attenuators with lengths ranging from 0.5 mm to 132.5 mm
  - Poisson noise is added to the Al transmission data for varying numbers of incident photons  $N_0$
  - Noiseless simulations of polyoxymethylene (POM) with continuous attenuation length for validation
- **Measurement conditions:**
  - Experimental setup consisting of a 150 kV transmission x-ray tube and a flat detector
  - 28 measurements of Al and POM attenuators with attenuation lengths ranging from 0.5 mm to 132.5 mm
  - Material for spectrum estimation: Al
  - Material for spectrum validation: POM

# Results

## Noiseless Simulated Data



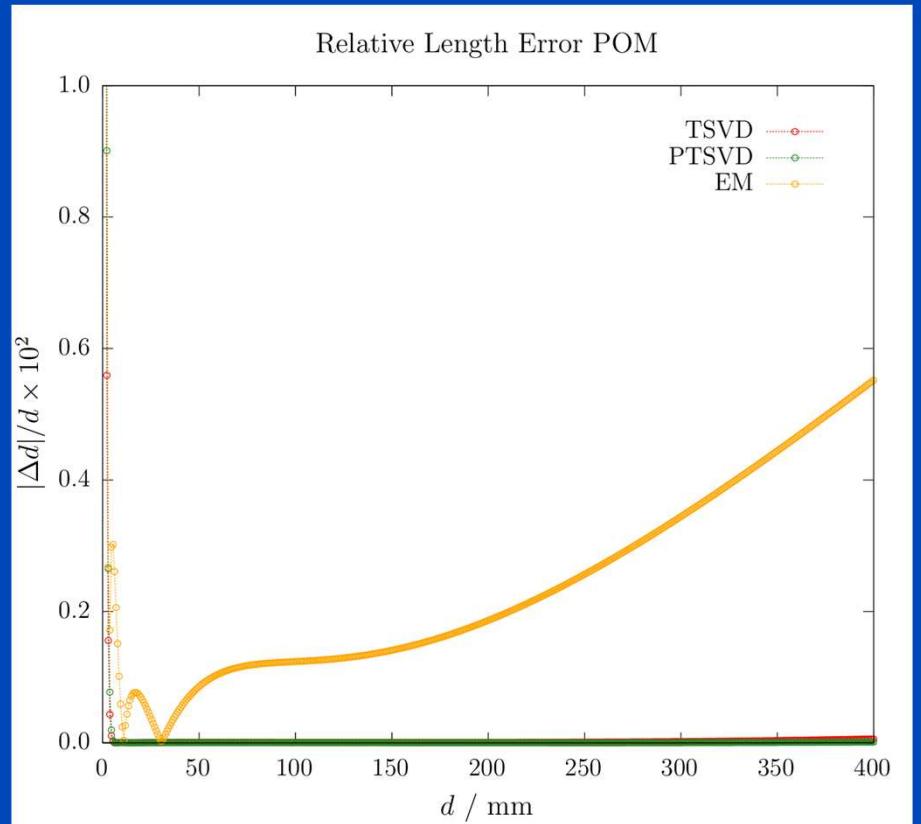
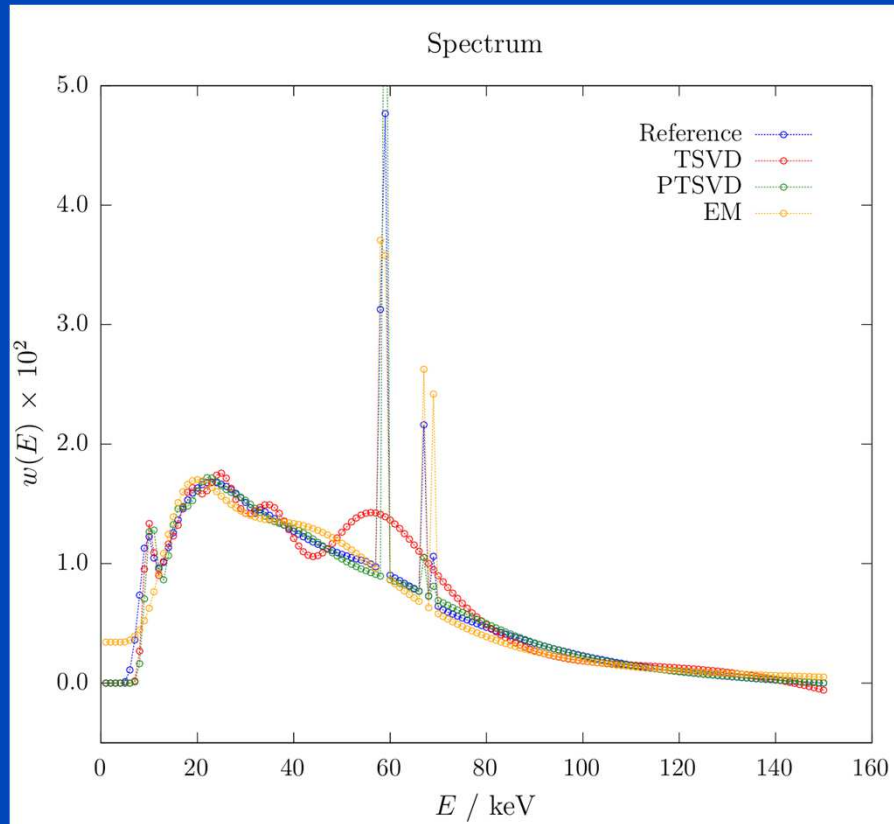
$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$



# Results

## Noisy Simulated Data

$N_0 = 1 \times 10^{12}$

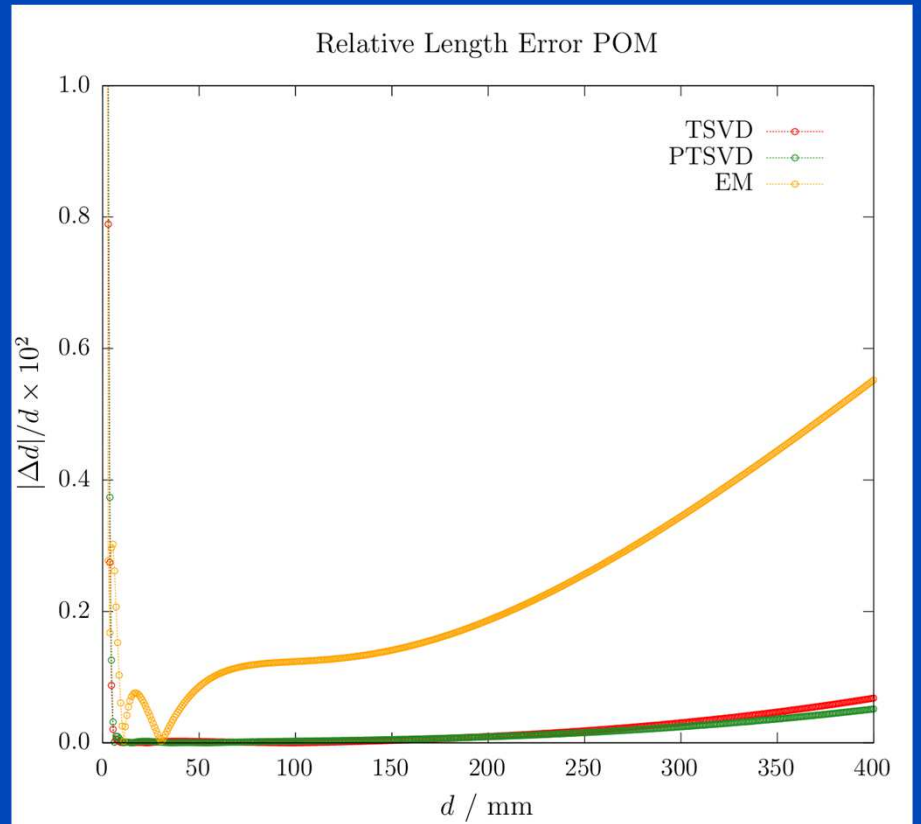
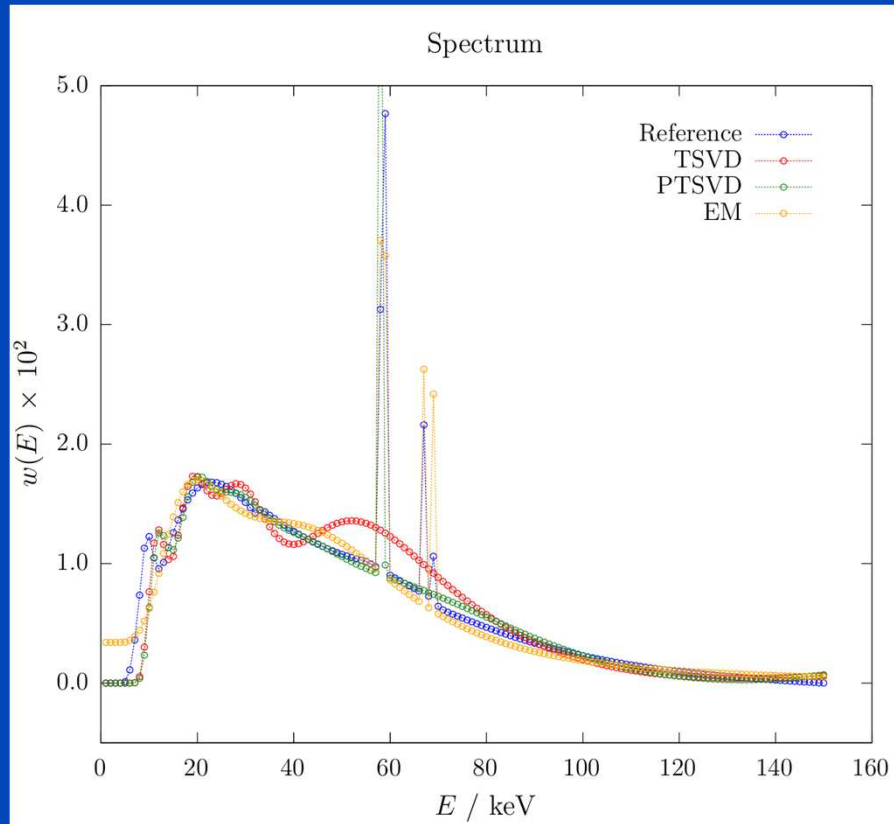


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

# Results

## Noisy Simulated Data

$N_0 = 1 \times 10^{10}$

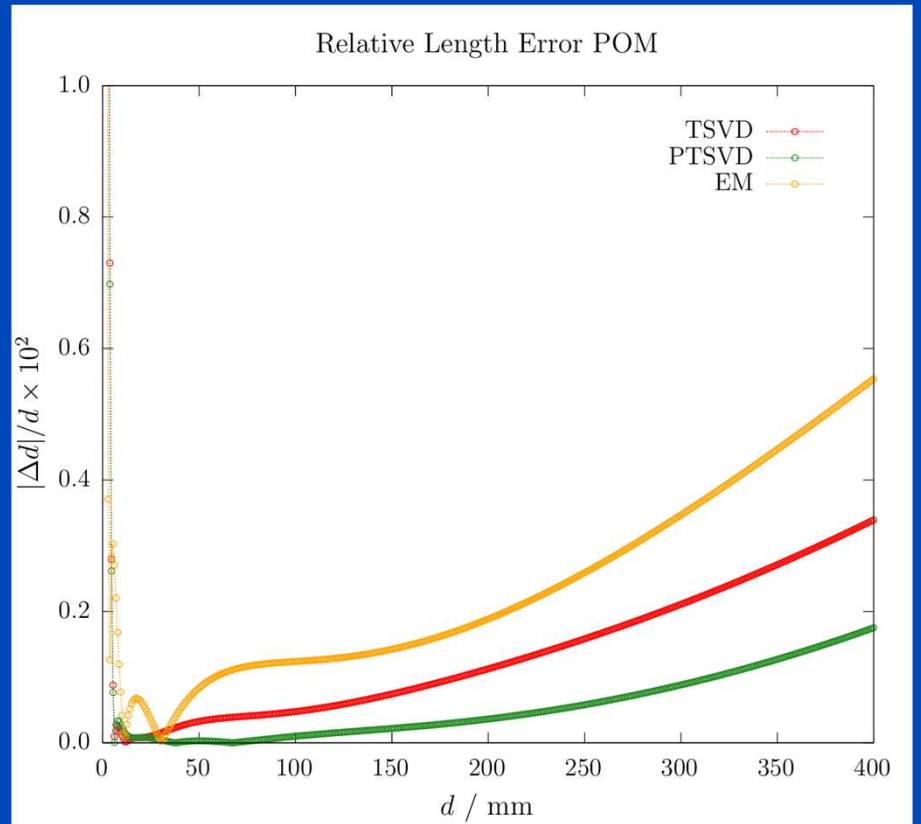
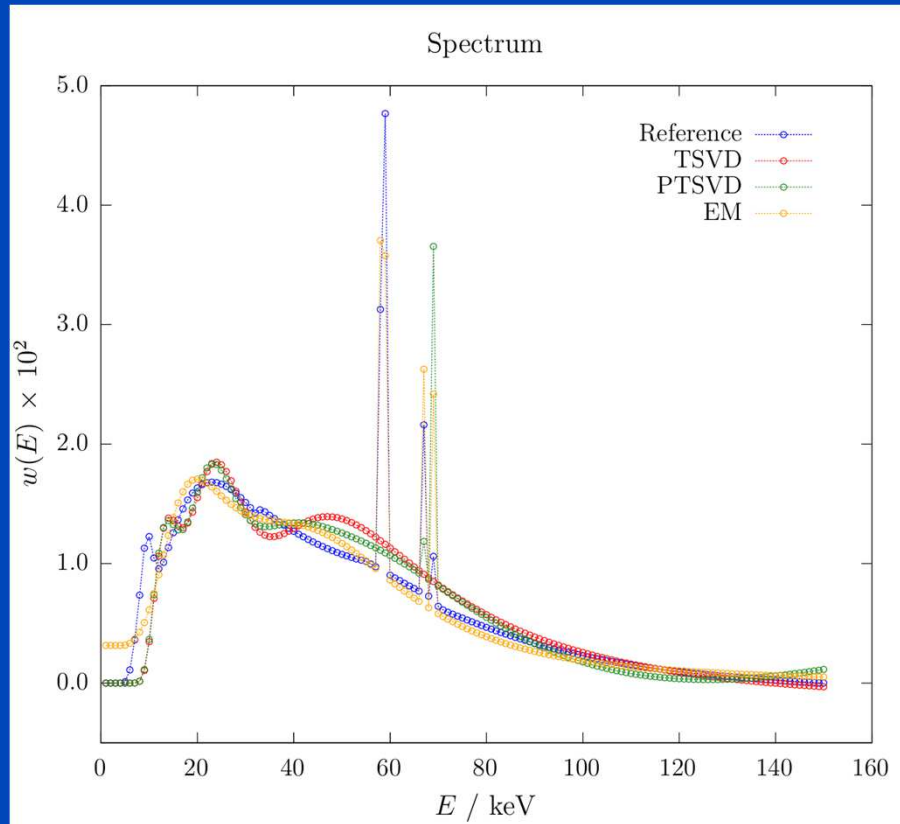


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

# Results

## Noisy Simulated Data

$N_0 = 1 \times 10^8$

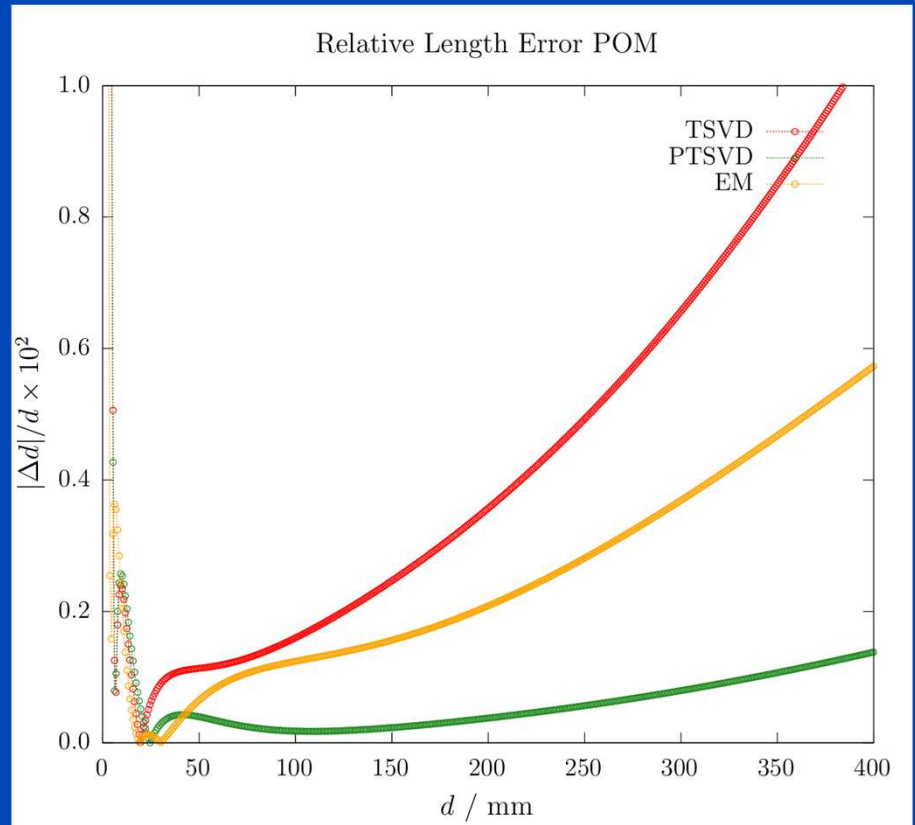
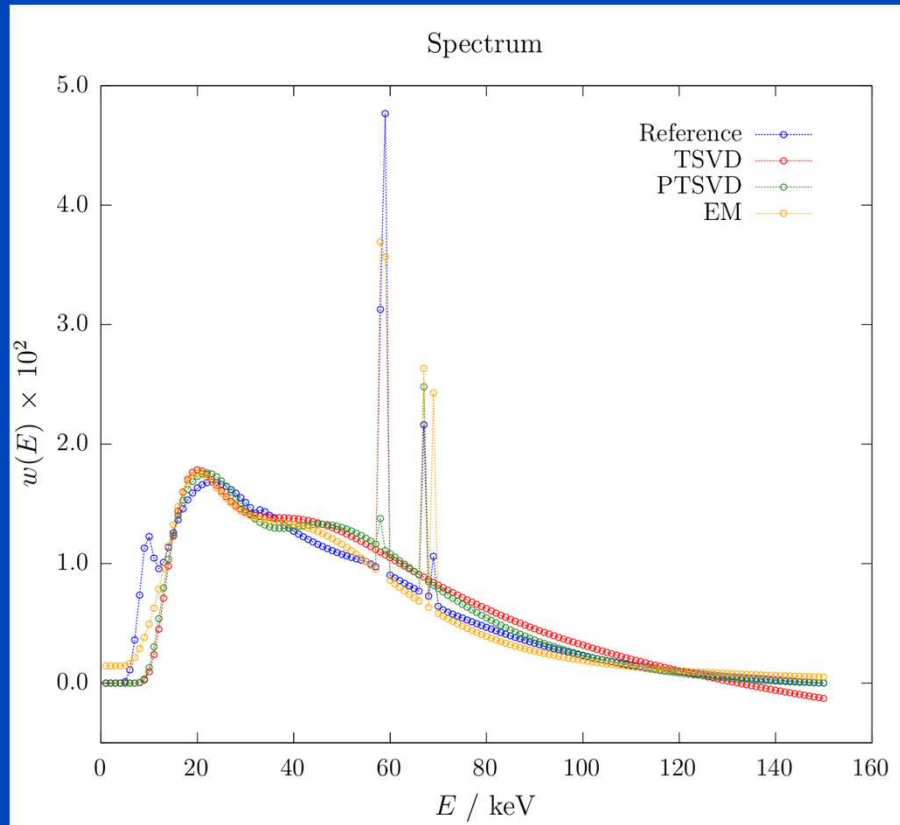


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

# Results

## Noisy Simulated Data

$N_0 = 1 \times 10^6$

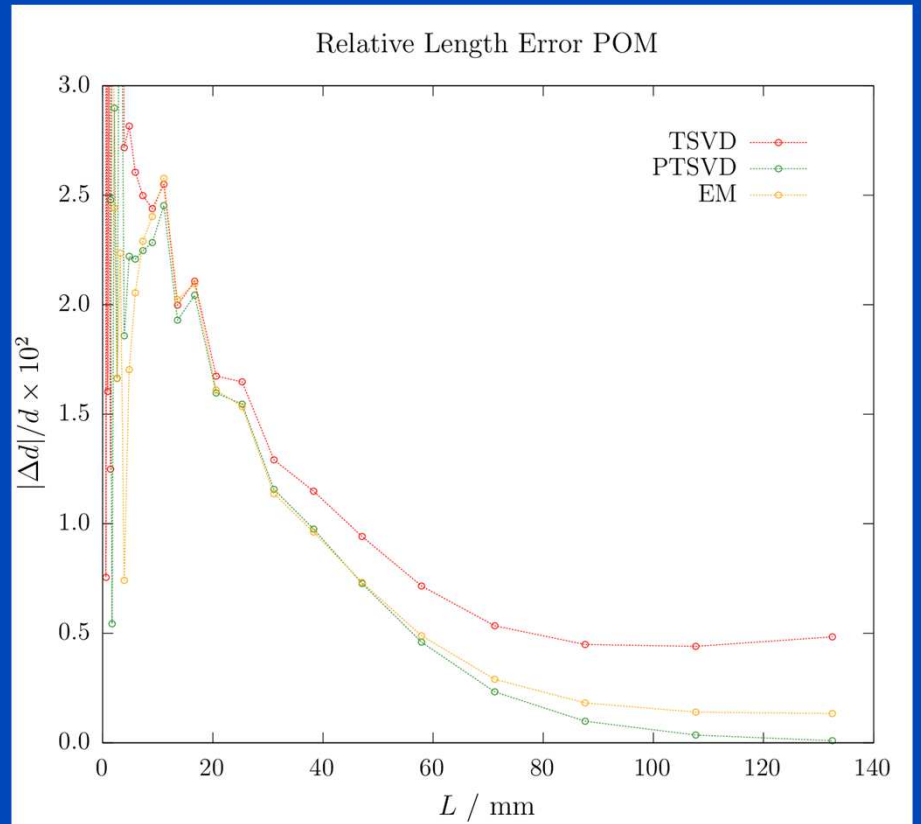
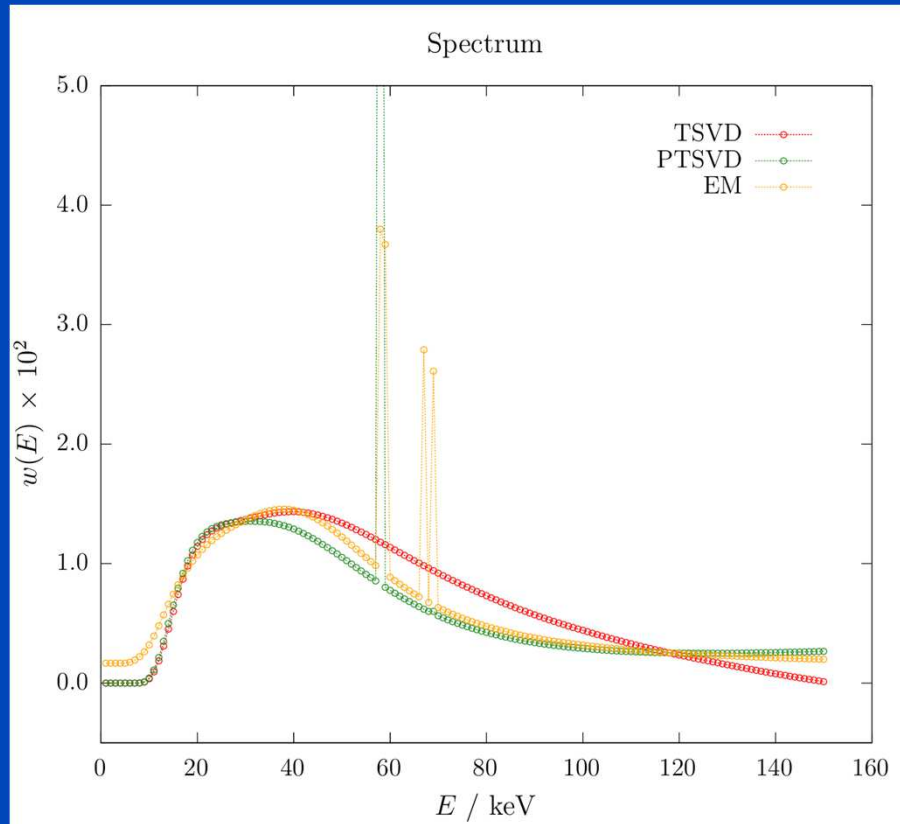


$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

# Results

## Measured Data

$N_0 \approx 1 \times 10^{10}$



$$\frac{|\Delta d|}{d} = \frac{|d' - d|}{d}$$

# Conclusion and Discussion

- PTSVD overcomes the limitations of TSVD by incorporating prior information about the statistical nature of the transmission data and about the high frequency components of the spectrum.
- PTSVD is less prone to noise compared to TSVD.
- Simulations show that for accurate transmission data PTSVD leads to smaller length errors compared to EM.
- Effects that limit the accuracy of transmission measurements: quantum noise, electronic noise, scattered radiation, image lag, quantization errors, dynamic range, ...

# Thank You!

This study was supported by AiF grant KF2301007NT3.

This presentation will soon be available at [www.dkfz.de/ct](http://www.dkfz.de/ct).

Job opportunities through DKFZ's international PhD or Postdoctoral Fellowship programs ([www.dkfz.de](http://www.dkfz.de)), or directly through Marc Kachelrieß ([marc.kachelriess@dkfz.de](mailto:marc.kachelriess@dkfz.de)).

Parts of the reconstruction software were provided by RayConStruct<sup>®</sup> GmbH, Nürnberg, Germany.